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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.	
10/044,268	01/08/2002	Charles Leu		7873	
25859	7590 08/07/2003				
WEI TE CHUNG FOXCONN INTERNATIONAL, INC. 1650 MEMOREX DRIVE SANTA CLARA, CA 95050			EXAMINER		
			PRITCHETT, JOSHUA L		
			ART UNIT	PAPER NUMBER	
			2872		
			DATE MAILED: 08/07/2003	DATE MAILED: 08/07/2003	

Please find below and/or attached an Office communication concerning this application or proceeding.

		Application No.	Applicant(s)			
Office Action Summary		10/044,268	LEU ET AL.			
		Examiner	Art Unit			
		Joshua L Pritchett	2872			
	The MAILING DATE of this communication appears on the cover sheet with the correspondence address Period for Reply					
A SHORTENED STATUTORY PERIOD FOR REPLY IS SET TO EXPIRE 3 MONTH(S) FROM THE MAILING DATE OF THIS COMMUNICATION. - Extensions of time may be available under the provisions of 37 CFR 1.136(a). In no event, however, may a reply be timely filed after SIX (6) MONTHS from the mailing date of this communication. - If the period for reply specified above is less than thirty (30) days, a reply within the statutory minimum of thirty (30) days will be considered timely. - If NO period for reply is specified above, the maximum statutory period will apply and will expire SIX (6) MONTHS from the mailing date of this communication. - Failure to reply within the set or extended period for reply will, by statute, cause the application to become ABANDONED (35 U.S.C. § 133). - Any reply received by the Office later than three months after the mailing date of this communication, even if timely filed, may reduce any earned patent term adjustment. See 37 CFR 1.704(b). Status						
1)⊠	Responsive to communication(s) filed on 30	<u>June 2003</u> .				
2a)⊠	This action is FINAL . 2b) ☐ TI	his action is non-final.	•			
3)	closed in accordance with the practice under Ex parte Quayle, 1935 C.D. 11, 453 O.G. 213.					
•	ion of Claims					
	Claim(s) 1-3 and 6-14 is/are pending in the a					
4a) Of the above claim(s) is/are withdrawn from consideration.						
·	Claim(s) is/are allowed.					
·	Claim(s) <u>1-3 and 6-14</u> is/are rejected.					
/ •	☑ Claim(s) <u>6</u> is/are objected to.					
-	Claim(s) are subject to restriction and/oion Papers	or election requirement.				
9)	The specification is objected to by the Examine	er.				
10)⊠ The drawing(s) filed on <u>08 January 2002</u> is/are: a)⊠ accepted or b)⊡ objected to by the Examiner.						
Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).						
11) ☐ The proposed drawing correction filed on is: a) ☐ approved b) ☐ disapproved by the Examiner.						
If approved, corrected drawings are required in reply to this Office action.						
12)☐ The oath or declaration is objected to by the Examiner.						
Priority under 35 U.S.C. §§ 119 and 120						
13) Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).						
a) ☐ All b) ☐ Some * c) ☐ None of:						
	1. Certified copies of the priority documen	ts have been received.				
	2. Certified copies of the priority documen					
 3. Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)). * See the attached detailed Office action for a list of the certified copies not received. 						
14) Acknowledgment is made of a claim for domestic priority under 35 U.S.C. § 119(e) (to a provisional application).						
 a) ☐ The translation of the foreign language provisional application has been received. 15)☐ Acknowledgment is made of a claim for domestic priority under 35 U.S.C. §§ 120 and/or 121. 						
Attachmen	t(s)					
1) Notice of References Cited (PTO-892) 2) Notice of Draftsperson's Patent Drawing Review (PTO-948) 3) Information Disclosure Statement(s) (PTO-1449) Paper No(s) 4) Interview Summary (PTO-413) Paper No(s) 5) Notice of Informal Patent Application (PTO-152) 6) Other:						
.S. Patent and T	rademark Office					

DETAILED ACTION

This action is in response to Amendment A filed June 30, 2003. Claims 1-3 and 8-11 have been amended, claims 4-5 have been canceled and claims 12-14 have been added as requested by the applicant.

Claim Objections

Claim 6 is objected to because of the following informalities: the amendment to claim 6 states "the thin film as described in claim 43." The examiner will examine the claim as if claim 6 depended from claim 3 because it appears that the number 4 was inadvertently not crossed out. Appropriate correction is required.

Claim Rejections - 35 USC § 103

The text of those sections of Title 35, U.S. Code not included in this action can be found in a prior Office action.

Claims 1, 7 and 11 are rejected under 35 U.S.C. 103(a) as being unpatentable over Pelekhaty in view of Mitsui.

Regarding claim 1, Pelekhaty teaches a thin film filter for dense wavelength division multiplexing, the filter comprising a glass substrate (200), a film stack comprising a plurality of

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cavities (178, 182, 180; Fig. 11) wherein each cavity comprises a first mirror layer (194 for cavity 180) and a second mirror layer (176 for cavity 180) on the glass substrate comprising low refractive index thin films (68) and high refractive index thin films (66), by stating that one film has a high refractive index and the other film has a low refractive index Pelekhaty inherently states that a substantial difference exists between the refractive index of the alternating layers (col. 6 lines 54-55). Pelekhaty lacks reference to the high refractive index thin film comprising indium tin oxide. Mitsui teaches the use of tin oxide including indium as a thin film light transmissive layer (col. 2 lines 27-29), and indium tin oxide is known to have a high refractive index. It would have been obvious to a person of ordinary skill in the art at the time the invention was made to use the indium tin oxide film taught by Mitsui in the Pelekhaty invention for the purpose of having a film with low resistance to light transmission and high scratch resistance.

Regarding claim 7, Pelekhaty teaches the invention as claimed but lacks reference to claimed composition of the indium tin oxide layer. Mitsui teaches the claimed composition (col. 2 lines 38-40). Mitsui teaches the compound having an indium content being between 0.1 and 30 percent and a gallium content of 0.1-30 percent. Therefore the claimed range of 17-20 percent of indium oxide and 83-80 percent of tin oxide is taught by the anticipated by Mitsui. It would have been obvious to a person of ordinary skill in the art at the time the invention was made to use the composition taught by Mitsui in the Pelekhaty invention for the purpose of having the thin film layer have low resistance to light transmission and a high resistance to scratching.

Regarding claim 11, Pelekhaty teaches a thin film filter for dense wavelength division multiplexing, the filter comprising a glass substrate (200), a film stack comprising a plurality of Art Unit: 2872

cavities (176, 182, 180; Fig. 11) on the glass substrate comprising low refractive index thin films (68) and high refractive index thin films (66). Pelekhaty further teaches the number of layers in a film stack with five cavities would be about 160. It has been held that it is within the ability of one of ordinary skill in the art to duplicate parts of a structure. The claim limitations relating to the number of cavities (5) and the number of layers (160) are obvious duplication of the known parts of the Pelekhaty reference, and therefore are not patentable over the prior art. Pelekhaty lacks reference to the high refractive index thin film comprising indium tin oxide. Mitsui teaches the use of tin oxide including indium as a thin film light transmissive layer (col. 2 lines 27-29), and indium tin oxide is known to have a refractive index of about 2.1. It would have been obvious to a person of ordinary skill in the art at the time the invention was made to use the indium tin oxide film taught by Mitsui in the Pelekhaty invention for the purpose of having a film with low resistance to light transmission and high scratch resistance. One would further have been motivated to duplicated the parts of Pelekhaty for the purpose of further eliminating any stray light in the output beam of the filter and thus making the filter transmission more selective.

Claims 2-3, 8-10 and 12-14 is rejected under 35 U.S.C. 103(a) as being unpatentable over Pelekhaty in view of Mitsui as applied to claims 1 and 11 above, and further in view of Adair (US 6,490,381).

Regarding claims 2 and 12, Pelekhaty in combination with Mitsui teaches the invention as claimed but lacks reference to a coupling film. Adair teaches the use of a coupling film (718) and the coupling film adjoins an adjacent cavity of the plurality of cavities (Fig. 7A). It would

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have been obvious to a person of ordinary skill in the art at the time the invention was made to include the coupling film of Adair in the Pelekhaty invention for the purpose of coherently coupling light between the successive cavities.

Regarding claims 3 and 13, Pelekhaty in combination with Mitsui teaches the invention as claimed including the use of an alternating refractive index structure (Fig. 11) but lacks reference to the coupling film having a low refractive index. Adair teaches that mirrors are formed of a stack of alternating dielectric films (col. 5 lines 54-55). It is commonly known in the art to have the high refractive index layer of the mirror contacting the cavity (see Pelekhaty Fig. 11 and Goosen Fig. 3). Based on Fig. 7A, the alternating formation of Adair and the commonly known practice of placing the high refractive index layer contacting the cavity Adair shows the coupling layer (718) to be a low refractive index film. It would have been obvious to one of ordinary skill in the art at the time the invention was made to have the coupling film be a low refractive index film as taught by Adair for the purpose of limiting the amount of light reflected between the interface of two adjoining cavity structures.

Regarding claims 8 and 14, Pelekhaty in combination with Mitsui teaches the invention as claimed but lacks reference to the low refractive index material being silicon or aluminum oxide. Adair teaches the use of silicon oxide (col. 6 line 46) as the low refractive index material in combination with indium tin oxide (col. 6 lines 20-21) as the high refractive index material. It would have been obvious to a person of ordinary skill in the art at the time the invention was made to have the low refractive index layer of Pelekhaty comprise silicon oxide as taught by Adair for the purpose of allowing the filter to be adjustable for use in a wider range of applications.

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Regarding claim 9, Pelekhaty teaches the high and low refractive index materials alternating in the film stack (Fig. 11).

Regarding claim 10, Pelekhaty teaches the high and low refractive index thin films have an optical thickness of one-quarter wavelength (col. 6 lines 54-55).

Claim 6 is rejected under 35 U.S.C. 103(a) as being unpatentable over Pelekhaty in view of Mitsui and Adair as applied to claim 3 above, and further in view of Goossen (US 5,914,804).

Pelekhaty in combination with Mitsui and Adair teaches the invention as claimed but lack reference to the optical thickness of the spacer layer being a multiple of a quarter wavelength. Goossen teaches a spacer layer with an optical thickness of one half wavelength (Fig. 3). One half wavelength is equal to two times a quarter wavelength. It would have been obvious to a person of ordinary skill in the art at the time the invention was made to have the spacer layer of Pelekhaty have the optical thickness taught by Goossen for the purpose of limiting the size of the film stack and therefore increasing the space efficiency of the optical filter.

Response to Arguments

Applicant's arguments filed June 30, 2003 have been fully considered but they are not persuasive.

On pages 5-7 of Amendment A, applicant argues that there is no motivation to combine the reference of Pelekhaty and Mitsui because they are not similar fields of endeavor. The examiner disagrees, because both use thin film optical properties to filter light so as to allow only

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the desired wavelengths to pass through the filter. Pelekhaty uses a Fabry-Perot filter as an add/drop filter and Mitsui uses the indium tin oxide layer to filter light visible light. The applicant further argues that the combination of the indium tin oxide layer of Mitsui with the Pelekhaty filter still does not teach the claimed invention because the current invention has a lessened internal stress to increase manufacture success rate. The limitation of the decreased internal stress is not present in the claim language and no evidence has been supplied to suggest unexpected results therefore the examiner views the rejection as proper.

On pages 7-8 of Amendment A, applicant argues that the claimed 160 layers of the current invention is neither taught nor suggested by the prior art. It has been held that the duplication of parts is within the ability of one of ordinary skill in the art. The prior art teaches all the distinct elements of the current invention and one of ordinary skill could have created more of them in the same structural layout as taught in the Pelekhaty to achieve the claimed 160 layers. Furthermore the term "about" allows a very broad interpretation of the number of layers, therefore the examiner views the rejection as proper.

Conclusion

Applicant's amendment necessitated the new ground(s) of rejection presented in this Office action. Accordingly, THIS ACTION IS MADE FINAL. See MPEP § 706.07(a). Applicant is reminded of the extension of time policy as set forth in 37 CFR 1.136(a).

A shortened statutory period for reply to this final action is set to expire THREE MONTHS from the mailing date of this action. In the event a first reply is filed within TWO

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MONTHS of the mailing date of this final action and the advisory action is not mailed until after the end of the THREE-MONTH shortened statutory period, then the shortened statutory period will expire on the date the advisory action is mailed, and any extension fee pursuant to 37 CFR 1.136(a) will be calculated from the mailing date of the advisory action. In no event, however, will the statutory period for reply expire later than SIX MONTHS from the date of this final action.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Joshua L Pritchett whose telephone number is 703-305-7917. The examiner can normally be reached on Monday - Friday 7:00 - 3:30.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Drew Dunn can be reached on 703-305-0024. The fax phone numbers for the organization where this application or proceeding is assigned are 703-872-9318 for regular communications and 703-872-9319 for After Final communications.

Any inquiry of a general nature or relating to the status of this application or proceeding should be directed to the receptionist whose telephone number is 703-308-0956.

JLP July 30, 2003

> Audrey Chang **Primary Examiner** Technology Center 2800